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BUK92150-55A

N-channel TrenchMOS logic level FET

12 June 2014

Product data sheet

1. General description

Logic level N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using TrenchMOS technology. This product has been designed and qualified to the appropriate AEC standard for use in automotive critical applications.

2. Features and benefits

- Low conduction losses due to low on-state resistance
- Q101 compliant
- Suitable for logic level gate drive sources
- Suitable for thermally demanding environments due to 175 °C rating

3. Applications

- 12 V and 24 V loads
- Automotive and general purpose power switching
- Motors, lamps and solenoids

4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
V_{DS}	drain-source voltage	$T_j \geq 25^\circ\text{C}; T_j \leq 175^\circ\text{C}$		-	-	55	V
I_D	drain current	$V_{GS} = 5\text{ V}; T_{mb} = 25^\circ\text{C}$; Fig. 2 ; Fig. 3		-	-	11	A
P_{tot}	total power dissipation	$T_{mb} = 25^\circ\text{C}$; Fig. 1		-	-	36	W
Static characteristics							
R_{DSon}	drain-source on-state resistance	$V_{GS} = 10\text{ V}; I_D = 5\text{ A}; T_j = 25^\circ\text{C}$		-	97	125	$\text{m}\Omega$
		$V_{GS} = 5\text{ V}; I_D = 5\text{ A}; T_j = 175^\circ\text{C}$; Fig. 11 ; Fig. 12		-	-	280	$\text{m}\Omega$
		$V_{GS} = 4.5\text{ V}; I_D = 5\text{ A}; T_j = 25^\circ\text{C}$		-	-	155	$\text{m}\Omega$
		$V_{GS} = 5\text{ V}; I_D = 5\text{ A}; T_j = 25^\circ\text{C}$; Fig. 11 ; Fig. 12		-	120	140	$\text{m}\Omega$
Dynamic characteristics							
Q_{GD}	gate-drain charge	$V_{GS} = 5\text{ V}; I_D = 5\text{ A}; V_{DS} = 44\text{ V}$; $T_j = 25^\circ\text{C}$; Fig. 13		-	2.6	-	nC



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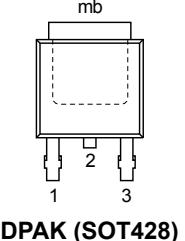
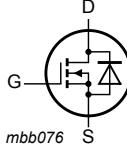
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Symbol	Parameter	Conditions		Min	Typ	Max	Unit
Avalanche ruggedness							
$E_{DS(AL)S}$	non-repetitive drain-source avalanche energy	$I_D = 11 \text{ A}$; $V_{sup} \leq 55 \text{ V}$; $R_{GS} = 50 \Omega$; $V_{GS} = 5 \text{ V}$; $T_{j(init)} = 25 \text{ }^\circ\text{C}$; unclamped		-	-	16	mJ

5. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate		
2	D	Drain		
3	S	source		
mb	D	mounting base; connected to drain		

6. Ordering information

Table 3. Ordering information

Type number	Package		
	Name	Description	Version
BUK92150-55A	DPAK	plastic single-ended surface-mounted package (DPAK); 3 leads (one lead cropped)	SOT428
BUK92150-55A/CD	DPAK	plastic single-ended surface-mounted package (DPAK); 3 leads (one lead cropped)	SOT428

7. Marking

Table 4. Marking codes

Type number	Marking code
BUK92150-55A	9215055A
BUK92150-55A/CD	

8. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage	$T_j \geq 25 \text{ }^\circ\text{C}$; $T_j \leq 175 \text{ }^\circ\text{C}$	-	55	V

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Symbol	Parameter	Conditions	Min	Max	Unit
V_{DGR}	drain-gate voltage	$R_{GS} = 20 \text{ k}\Omega$	-	55	V
V_{GS}	gate-source voltage		-15	15	V
P_{tot}	total power dissipation	$T_{mb} = 25 \text{ }^{\circ}\text{C}$; Fig. 1	-	36	W
I_D	drain current	$T_{mb} = 25 \text{ }^{\circ}\text{C}$; $V_{GS} = 5 \text{ V}$; Fig. 2 ; Fig. 3	-	11	A
		$T_{mb} = 100 \text{ }^{\circ}\text{C}$; $V_{GS} = 5 \text{ V}$; Fig. 3	-	7.8	A
I_{DM}	peak drain current	$T_{mb} = 25 \text{ }^{\circ}\text{C}$; pulsed; $t_p \leq 10 \mu\text{s}$; Fig. 2	-	44	A
T_{stg}	storage temperature		-55	175	$^{\circ}\text{C}$
T_j	junction temperature		-55	175	$^{\circ}\text{C}$
Source-drain diode					
I_S	source current	$T_{mb} = 25 \text{ }^{\circ}\text{C}$	-	11	A
I_{SM}	peak source current	pulsed; $t_p \leq 10 \mu\text{s}$; $T_{mb} = 25 \text{ }^{\circ}\text{C}$	-	44	A
Avalanche ruggedness					
$E_{DS(AL)S}$	non-repetitive drain-source avalanche energy	$I_D = 11 \text{ A}$; $V_{sup} \leq 55 \text{ V}$; $R_{GS} = 50 \Omega$; $V_{GS} = 5 \text{ V}$; $T_{j(init)} = 25 \text{ }^{\circ}\text{C}$; unclamped	-	16	mJ

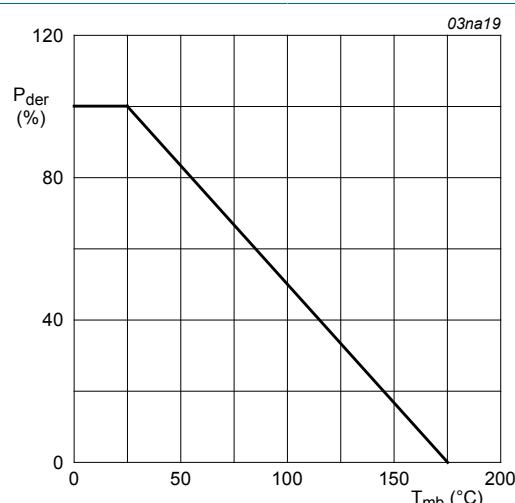


Fig. 1. Normalized total power dissipation as a function of mounting base temperature

$$P_{der} = \frac{P_{tot}}{P_{tot(25{}^{\circ}\text{C})}} \times 100 \%$$

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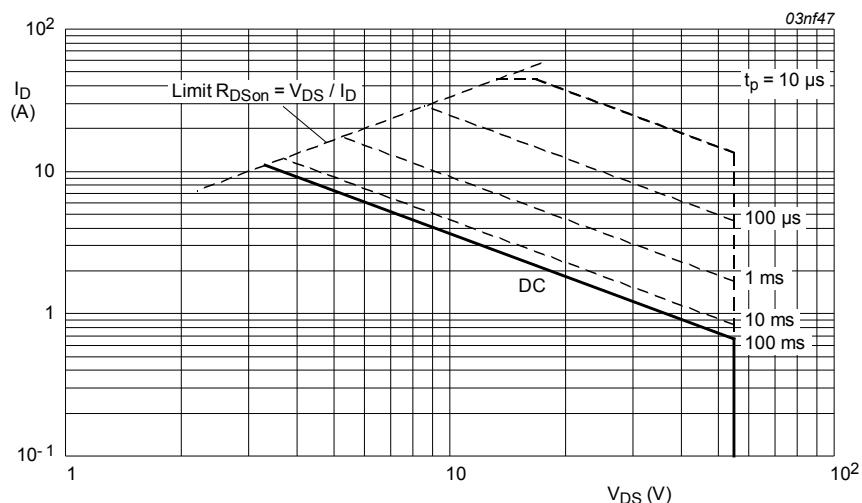


Fig. 2. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

$T_{mb} = 25^\circ C$; I_{DM} is single pulse

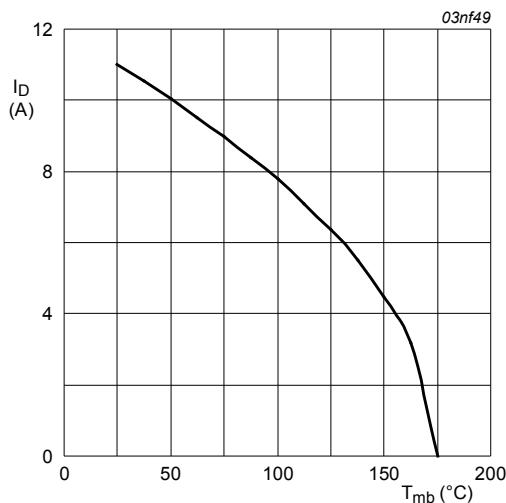


Fig. 3. Continuous drain current as a function of mounting base temperature

$$V_{GS} \geq 4.5V \quad I_{der} = \frac{I_D}{I_{D(25^\circ C)}} \times 100\%$$

9. Thermal characteristics

Table 6. Thermal characteristics

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
$R_{th(j-mb)}$	thermal resistance from junction to mounting base	Fig. 4		-	-	4.1	K/W
$R_{th(j-a)}$	thermal resistance from junction to ambient			-	71.4	-	K/W

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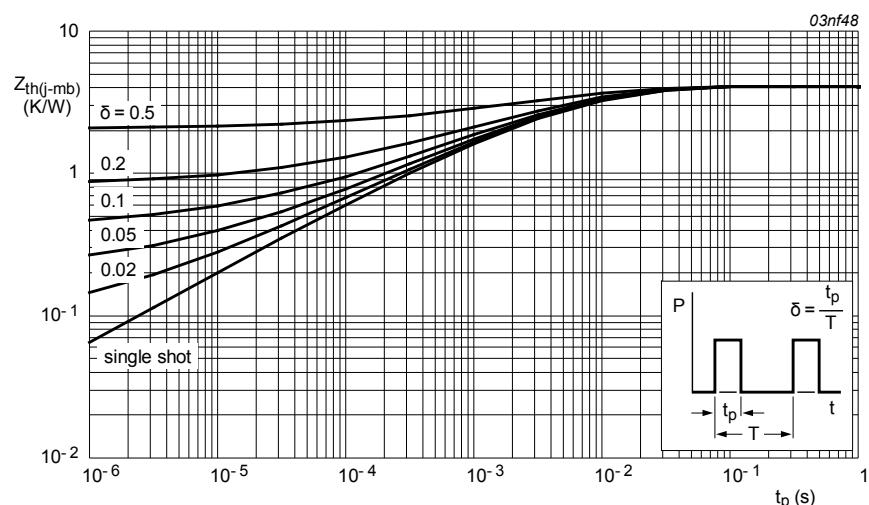


Fig. 4. Transient thermal impedance from junction to ambient as a function of pulse duration

10. Characteristics

Table 7. Characteristics

Symbol	Parameter	Conditions		Min	Typ	Max	Unit
Static characteristics							
V _{(BR)DSS}	drain-source breakdown voltage	I _D = 0.25 mA; V _{GS} = 0 V; T _j = 25 °C		55	-	-	V
		I _D = 0.25 mA; V _{GS} = 0 V; T _j = -55 °C		50	-	-	V
V _{GS(th)}	gate-source threshold voltage	I _D = 1 mA; V _{DS} = V _{GS} ; T _j = -55 °C; Fig. 10		-	-	2.3	V
		I _D = 1 mA; V _{DS} = V _{GS} ; T _j = 25 °C; Fig. 10		1	1.5	2	V
		I _D = 1 mA; V _{DS} = V _{GS} ; T _j = 175 °C; Fig. 10		0.5	-	-	V
I _{DSS}	drain leakage current	V _{DS} = 55 V; V _{GS} = 0 V; T _j = 175 °C		-	-	500	µA
		V _{DS} = 55 V; V _{GS} = 0 V; T _j = 25 °C		-	0.05	10	µA
I _{GSS}	gate leakage current	V _{GS} = 10 V; V _{DS} = 0 V; T _j = 25 °C		-	2	100	nA
		V _{GS} = -10 V; V _{DS} = 0 V; T _j = 25 °C		-	2	100	nA
R _{DSon}	drain-source on-state resistance	V _{GS} = 10 V; I _D = 5 A; T _j = 25 °C		-	97	125	mΩ
		V _{GS} = 5 V; I _D = 5 A; T _j = 175 °C; Fig. 11 ; Fig. 12		-	-	280	mΩ
		V _{GS} = 4.5 V; I _D = 5 A; T _j = 25 °C		-	-	155	mΩ
		V _{GS} = 5 V; I _D = 5 A; T _j = 25 °C; Fig. 11 ; Fig. 12		-	120	140	mΩ

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Symbol	Parameter	Conditions		Min	Typ	Max	Unit
Dynamic characteristics							
$Q_{G(\text{tot})}$	total gate charge	$I_D = 5 \text{ A}; V_{DS} = 44 \text{ V}; V_{GS} = 5 \text{ V};$ $T_j = 25^\circ\text{C}$; Fig. 13		-	6	-	nC
Q_{GS}	gate-source charge			-	0.76	-	nC
Q_{GD}	gate-drain charge			-	2.6	-	nC
C_{iss}	input capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz};$ $T_j = 25^\circ\text{C}$; Fig. 14		-	240	338	pF
C_{oss}	output capacitance			-	50	65	pF
C_{rss}	reverse transfer capacitance			-	40	58	pF
$t_{d(on)}$	turn-on delay time	$V_{DS} = 20 \text{ V}; R_L = 3.3 \Omega; V_{GS} = 5 \text{ V};$ $R_{G(\text{ext})} = 10 \Omega; T_j = 25^\circ\text{C}$		-	8	-	ns
t_r	rise time			-	57	-	ns
$t_{d(off)}$	turn-off delay time			-	16	-	ns
t_f	fall time			-	13	-	ns
L_D	internal drain inductance	measured from drain to centre of die; $T_j = 25^\circ\text{C}$		-	2.5	-	nH
L_S	internal source inductance	measured from source lead to source bond pad; $T_j = 25^\circ\text{C}$		-	7.5	-	nH
Source-drain diode							
V_{SD}	source-drain voltage	$I_S = 15 \text{ A}; V_{GS} = 0 \text{ V}; T_j = 25^\circ\text{C}$; Fig. 15		-	0.85	1.2	V
t_{rr}	reverse recovery time	$I_S = 20 \text{ A}; dI_S/dt = -100 \text{ A}/\mu\text{s};$ $V_{GS} = -10 \text{ V}; V_{DS} = 30 \text{ V}; T_j = 25^\circ\text{C}$		-	24	-	ns
Q_r	recovered charge			-	26	-	nC

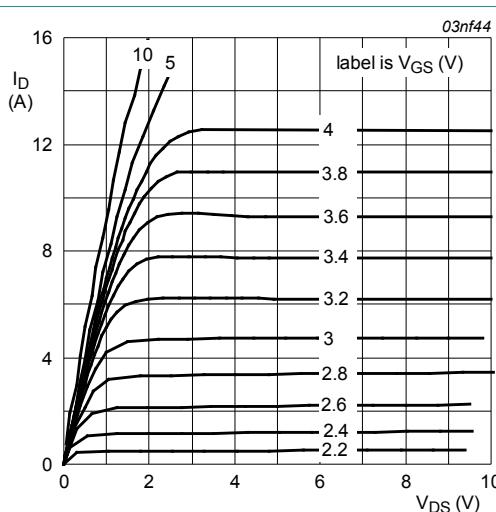


Fig. 5. Output characteristics: drain current as a function of drain-source voltage; typical values

$T_j = 25^\circ\text{C}$

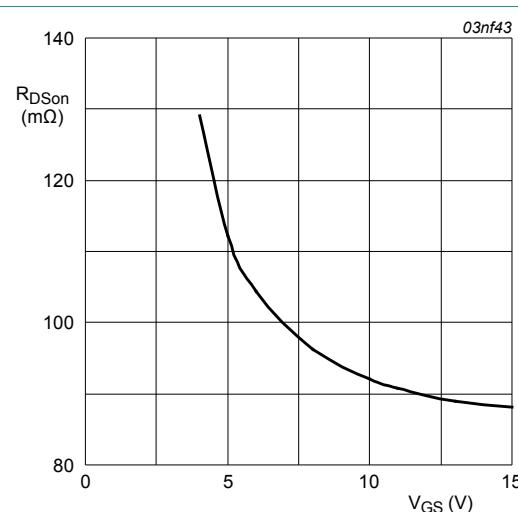


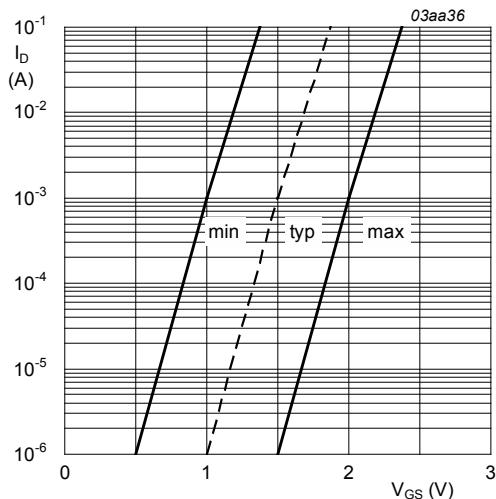
Fig. 6. Drain-source on-state resistance as a function of gate-source voltage; typical values

$T_j = 25^\circ\text{C}; I_D = 5\text{A}$

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$T_j = 25^\circ\text{C}$; $V_{DS} = 5\text{ V}$

Fig. 7. Sub-threshold drain current as a function of gate-source voltage

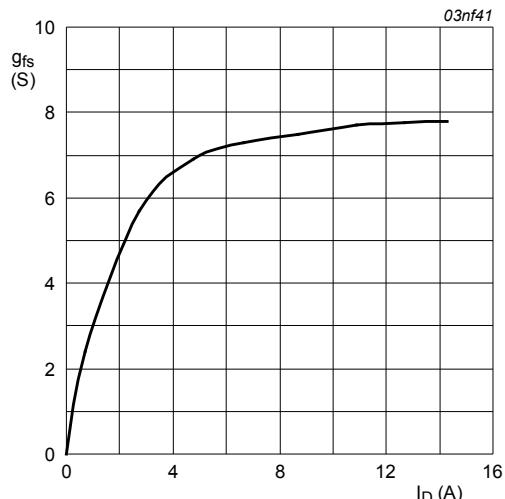


Fig. 8. Forward transconductance as a function of drain current; typical values

$T_j = 25^\circ\text{C}$; $V_{DS} = 25\text{ V}$

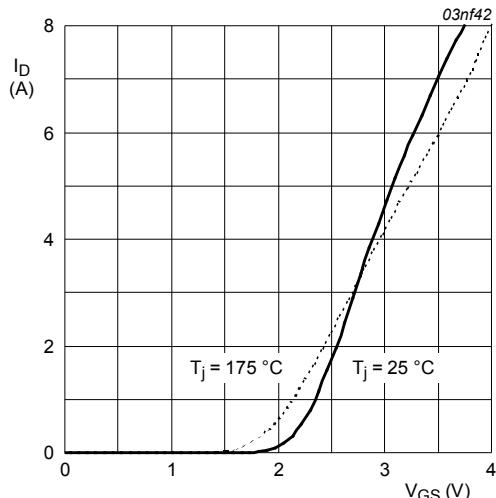


Fig. 9. Transfer characteristics: drain current as a function of gate-source voltage; typical values

$V_{DS} = 25\text{ V}$

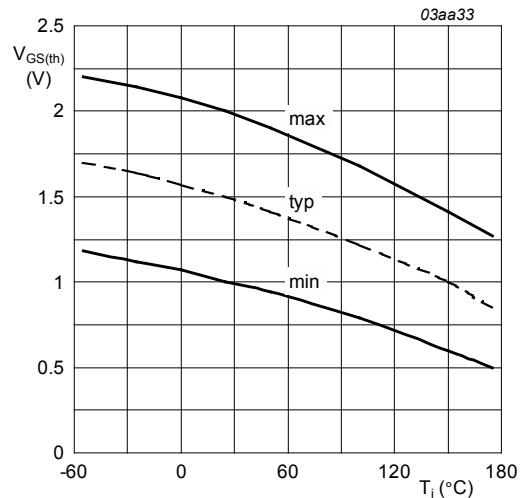


Fig. 10. Gate-source threshold voltage as a function of junction temperature

$I_D = 1\text{ mA}$; $V_{DS} = V_{GS}$

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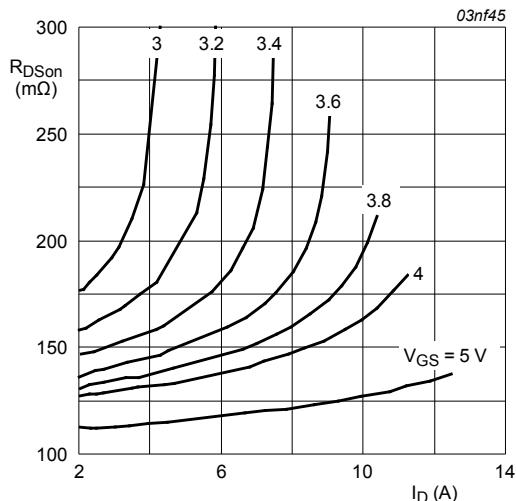


Fig. 11. Drain-source on-state resistance as a function of drain current; typical values

$T_j = 25^\circ\text{C}$

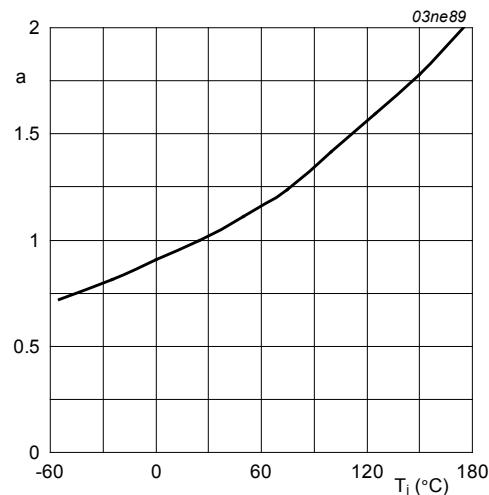


Fig. 12. Normalized drain-source on-state resistance factor as a function of junction temperature

$$a = \frac{R_{DSon}}{R_{DSon}(25^\circ\text{C})}$$

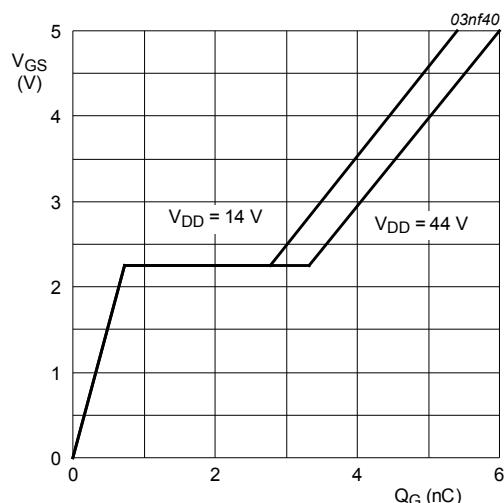


Fig. 13. Gate-source voltage as a function of gate charge; typical values

$T_j = 25^\circ\text{C}; I_D = 5\text{A}$

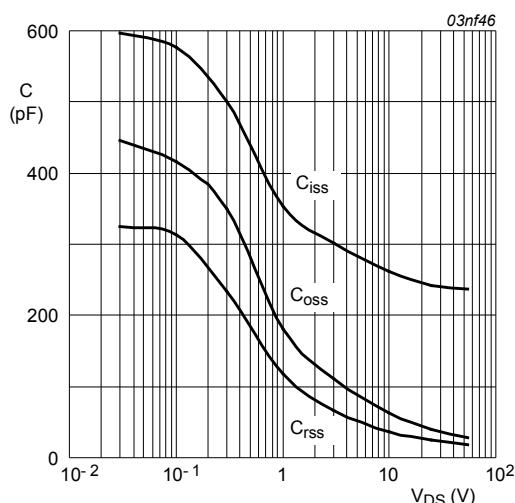
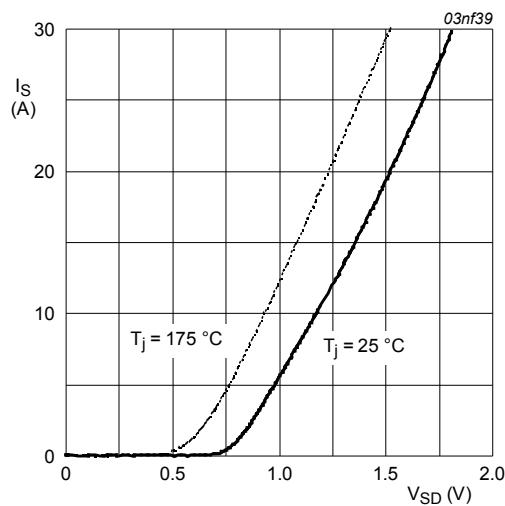


Fig. 14. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values

$V_{GS} = 0\text{V}; f = 1\text{MHz}$

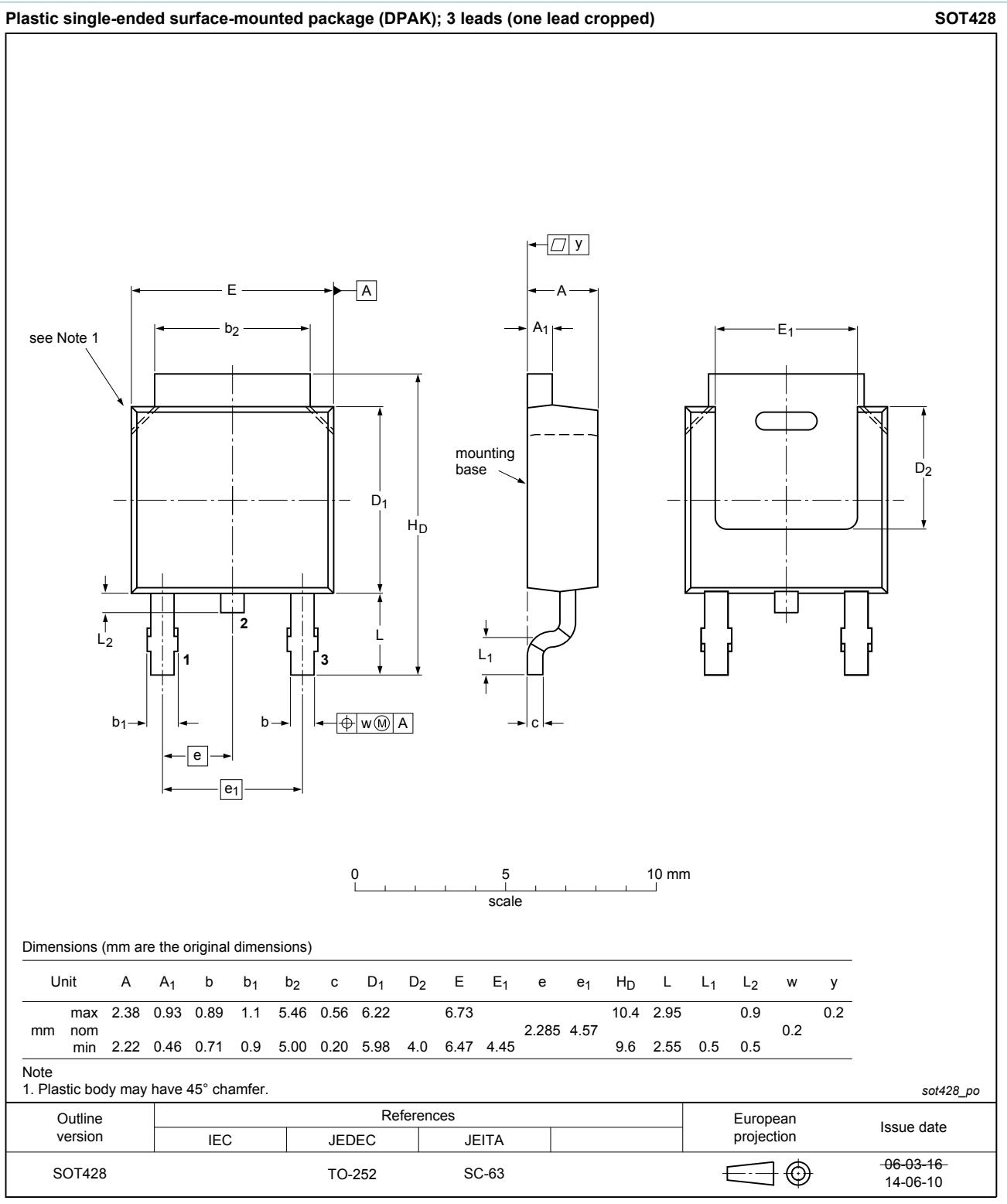
NXP Semiconductors**BUK92150-55A****N-channel TrenchMOS logic level FET****Fig. 15. Reverse diode current as a function of reverse diode voltage; typical values** $V_{GS} = 0V$

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11. Package outline



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12. Legal information

12.1 Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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